



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re DIVISIONAL Application of )  
Shunpei YAMAZAKI )  
Based On Serial No. 08 857,556 ) Art Unit: 2811  
Which Was Filed: May 16, 1997 ) Examiner: S. Crane  
For: METHOD OF FORMING INSULATING )  
FILMS, CAPACITANCES, AND )  
SEMICONDUCTOR DEVICES ) Date: July 20, 2000

INFORMATION DISCLOSURE STATEMENT

Honorable Assistant Commissioner for Patents  
Washington, D.C. 20231


Sir:

In accordance with the provisions of 37 C.F.R. 1.56 and 37 C.F.R. 1.97-1.99, it is requested that the references listed on the attached Form PTO-1449 be made of record in the above-identified application.

The references listed on the attached Form PTO-1449 were cited in parent application Serial No. 08 857,556 filed May 16, 1997, and the predecessor

applications including Serial Nos. 08-250,344 filed May 27, 1994, and the predecessor applications including Serial No. 08-041,520, filed March 30, 1993; and Serial No. 07-729,533, filed July 5, 1991.

Respectfully submitted,

A handwritten signature in cursive script, appearing to read "Jeffrey L. Costellia", is written over a horizontal line.

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Form PTO-1449  
(Rev. 8-83)U.S. Department of Commerce  
Patent and Trademark Office

Attorney Docket No. 0756-2183

Serial No. Not Yet Assigned

**INFORMATION DISCLOSURE STATEMENT**

(Use several sheets if necessary)

Applicant: Shunpei YAMAZAKI

Filing Date: July 20, 2000

Group: 2811

JCN 77 U.S. PTO  
09/620368**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
	4,849,081	7/18/89	Ross			
	3,607,679	9/1971	Melroy et al.			
	3,607,697	9/1971	Shirn et al.			
	3,616,400	10/1971	Wasa et al.			
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	4,732,659	3/1988	Schachter et al.			
	4,790,920	12/1988	Krzanich			
	4,804,640	2/1989	Kaganowicz et al.			
	4,883,543	11/1989	Gossen, Jr. et al.			

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26-40078	7/8/90	France				X
02-61128	11/1987	Japan				
10-96925	12/1967	Great Britain				

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

	Young et al., "Correlation... Ta <sub>2</sub> O <sub>5</sub> films", J. Fac. Sci. Technol., Vol. 14, No. 1, Jan/Feb 1977.
	Schrieber et al., J. Electrochem Soc., Vol. 123, No. 1, pp. 30-33 (1976)
	Suyama et al., "Electrical Conduction Mechanism and Breakdown Property in Sputter-Deposited Silicon Dioxide Films on Polycrystalline Silicon", J. Appl. Phys. Vol. 65, No. 1, 1 January 1989, pp. 210-214
	Jones et al., "Effect of Oxygen on the rf-Sputtering Rate of SiO <sub>2</sub> ", J. Vacuum Sci. and Technology, Vol. 5, No. 3, pp. 84-87.
	Kozuma et al., "Some Properties of Silica Film Made by RF Glow Discharge Sputtering", J. Jap. of Appl. Phys., vol. 9, No. 8, August 1970, pp. 983-91.
	Suyama et al., Chem. Abstracts 109573w, March 12, 1990, p. 750.

Examiner

Date Considered

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	Croteau et al., "Growth and Characterisation of PD(Zr, Ti) <sup>03</sup> Films Deposited by Reactive Sputtering of Metallic Targets" Proceedings of the Sixth IEEE International Symposium on Applications of Ferroelectrics, pp. 606-609, 1986.
	definition from Merriam Webster Collegiate Dictionary, Tenth Edition
	IEDM 11-14 Dec. 1988, pp. 222-225, San Francisco, Calif., U.S.; H. Takato et al., "High Performance CMOS Surrounding Gate Transistor (SGT) for Ultra High Density LSIs".
	Mizuno et al., "High Speed and Highly Reliable Trench MOSFET with Dual Gate", Symp. VLSI Tech. Dig. (1988), pp. 23-24.
	Young et al., "Effect of Pulse Duration on the Annealing of Ion Implanted Silicon With a XeCl Excimer Laser and Solar Cells", Mat. Res. Soc. Symp. Proc., Vol. 13, 1983, pp. 401-406.
	Schreiber et al., "High Quality RF-Sputtered Silicon Dioxide Layers", J. Electrochem. Soc., Vol. 123, No. 1, 1976, pp. 30-31.

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	5,136,534	8/1992	McDavid et al.			
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	5,403,763	4/4/95	Yamazaki			
	5,587,340	12/24/96	Yamazaki			
	5,464,780	11/7/95	Yamazaki			
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	4,937,641	6/26/90	Sunami et al.			
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	4,250,519	2/10/81	Mogi et al.			
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	5,189,503	2/23/93	Suguro			
	5,136,534	08/04/92	McDavid et al.			

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WO 89/02655	03/23/89	PCT			Full
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JP 62-23117	1/31/87	Japan			Abstract
JP 62-298119	12/25/87	Japan			Abstract
JP 02-47256	2/16/90	Japan			Abstract
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63-199456	8/17/88	Japan			X
1-248557	10/4/89	Japan			X
2-79475	3/20/90	Japan			X

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	JP 59-99726	6/8/84	Japan			Abstract	
	JP 64-82557	03/28/89	Japan			Abstract	
	JP 01-225148	09/08/89	Japan			Abstract	
	JP 04-61337	02/27/92	Japan			Abstract	
	60-005555	01/12/85	Japan			Abstract	
	60-218472	11/01/85	Japan			Abstract	
	61-119045	06/06/86	Japan			Abstract	
	62-056570	03/12/87	Japan			Abstract	
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	1-218054	08/31/89	Japan			Abstract	

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